Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/056,080	SHIN-ICHIROU HARASAWA
Examiner	Art Unit
Tran O Le	2633

	SEARCHED				
Class	Subclass	Date	Examiner		
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"	23,32,33	2/11/2005	TQL		
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INT	NTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
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SEAR((INCLUDING SE	CH NOTES	RATEGY)
		DATE	EXMR
Jason C.	2	/11/2005	TQL
Inventor check	. 2	//11/2005 ·	TQL
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